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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 11685-2003

Replacing GB/T 8992-1988; GB/T 11685-1989

**Measurement procedures for semiconductor X-ray detector
system and semiconductor X-ray energy spectrometers
(English Translation)**

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This standard specifies the semiconductor X-ray sonar system and semiconductor X-ray energy dispersive spectroscopy method the amount of the main characteristics of the side. This standard applies to semiconductor X-ray sonar system and semiconductor X-ray energy dispersive properties of the main playing side of a.

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